AMENDMENTS TO THE CLAIMS:

The following listing of claims replaces all prior listings, and all prior versions, of claims in the application.

LISTING OF CLAIMS:

1. – 10. (Cancelled).

11.   (New) A manufacturing method of a semiconductor integrated circuit device, comprising:

(a)   storing apparatus log data that are data outputted from semiconductor manufacturing apparatus that processes a semiconductor wafer, contain a plurality of headers and show a state of the semiconductor manufacturing apparatus in an apparatus log data memory;

(b)   detecting whether there are abnormal data in the apparatus log data stored in the apparatus log data memory or not at an abnormal data detector; and

(c)   outputting a result detected at the abnormal data detector to a result output portion,

wherein the process (b) includes lower rank processes below:

(b1)   acquiring a search key assigning the header of the apparatus log data;

(b2)   extracting past data coinciding with the apparatus log data in a content of the header assigned with the acquired search key from a past data memory;

(b3)   calculating a standard deviation from the extracted past data; and

(b4)   detecting based on the calculated standard deviation whether the abnormal data are present in the apparatus log data or not,

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wherein, of assignment of the header with the search key, an assignment of an apparatus name is grouped to enable to apply on a group base.